

PATENT ABSTRACTS OF JAPAN

(11)Publication number : 08-330405

(43)Date of publication of application : 13.12.1996

(51)Int.CI.

H01L 21/68

B23Q 3/15

H02N 13/00

(21)Application number : 08-016164

(71)Applicant : APPLIED MATERIALS INC

(22)Date of filing : 31.01.1996

(72)Inventor : CHEN AIHUA
PARKHE VIJAY
EDELSTEIN SERGIO

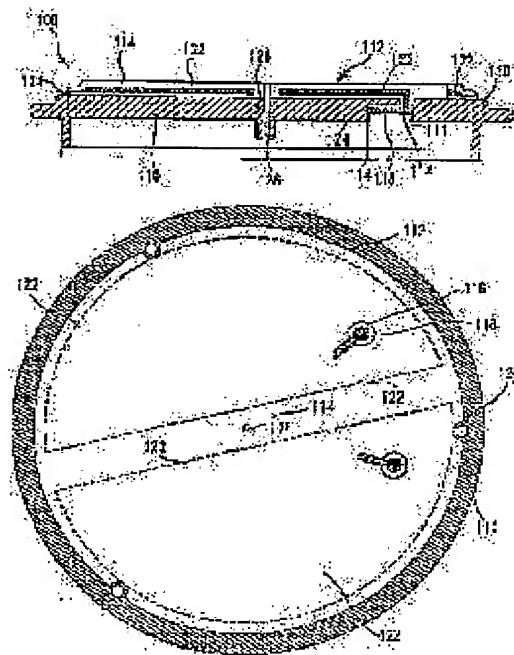
(30)Priority

Priority number : 95 381258 Priority date : 31.01.1995 Priority country : US

(54) HIGH-TEMPERATURE POLYIMIDE ELECTROSTATIC CHUCK

(57)Abstract:

PROBLEM TO BE SOLVED: To supply an electric connector enabling operation at a high temperature for a conductive layer in an electrostatic chuck 3 from a DC power source by providing one polyimide-providing film operating as a dielectric layer in the electrostatic chuck and permitting the polyimide providing film to have a specified durable operation temperature.



SOLUTION: An upper second polyimide providing film 114 operating as the dielectric layer, the inner conductive layer 122 having a patterning and a lower first polyimide providing film 124 are provided in an electrostatic chuck means 112. The first and second polyimide providing films 124 and 114 are provided with a withstand operation temperature of 175° C, and conductive extension parts 116 are provided for the opening part 111 in a supporting platen 110 by positioning pins 120, so as to arrange them. Then, the positions on the supporting platen 110 are given relatively. Thus, the lower polyimide providing film 124 is adhered to the supporting platen 110. Consequently, the electric connector which realizes operation at a high temperature can be supplied into the electrostatic chuck 112.

LEGAL STATUS

[Date of request for examination]

[Date of sending the examiner's decision of rejection]

[Kind of final disposal of application other than the examiner's decision of rejection or application converted registration]

[Date of final disposal for application]

[Patent number]

[Date of registration]

[Number of appeal against examiner's decision of rejection]

[Date of requesting appeal against examiner's decision of rejection]

[Date of extinction of right]

Copyright (C); 1998,2003 Japan Patent Office